

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. ITL.0725D1US (P14251D)	SERIAL NO. 10/643,427		
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<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KR	A.	US 2001/0055836 A1	12/27/2001	Kunda			
KR	B.	6,140,144	10/31/2000	Najafi et al.			
	C.						
	D.						
	E.						
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KR	G.	EP 0 994 330 A1	04/19/2000	EPO			
	H.						
	I.						
	J.						
	K.						
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EXAMINER <i>[Signature]</i>			DATE CONSIDERED 10/7/04				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							